STI150N10F7, STP150N10F7

N-channel 100 V, 0.0036 Ω typ., 110 A, STripFET™ F7 Power MOSFETs in I^2PAK and TO-220 packages

Datasheet — production data

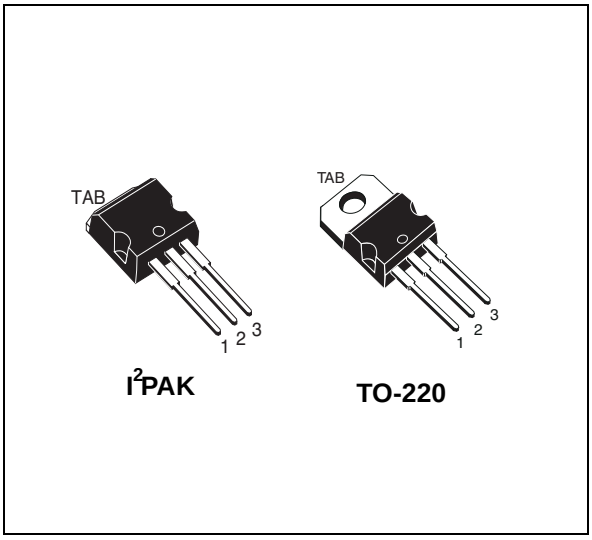
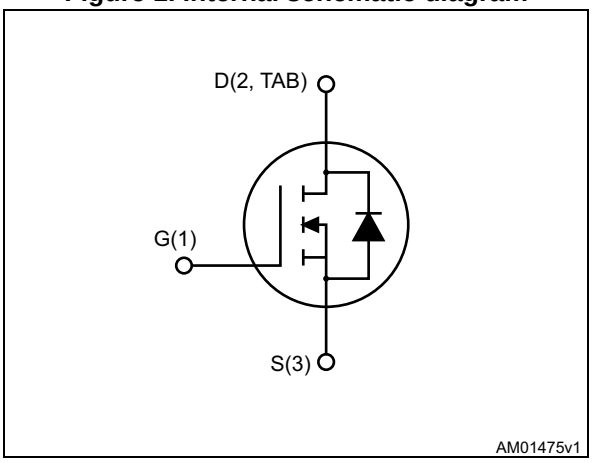


Figure 1. Internal schematic diagram



Features

Order codes	V_{DS}	$R_{DS(on)max}$	I_D	P_{TOT}
STI150N10F7	100 V	0.0042 Ω	110 A	250 W
STP150N10F7				

- Among the lowest $R_{DS(on)}$ on the market
- Excellent figure of merit (FoM)
- Low Crss/Ciss ratio for EMI immunity
- High avalanche ruggedness

Applications

- Switching applications

Description

These N-channel Power MOSFETs utilize STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1. Device summary

Order codes	Marking	Package	Packaging
STI150N10F7	150N10F7	I^2PAK	Tube
STP150N10F7		TO-220	

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	100	V
V_{GS}	Gate- source voltage	±20	V
I_D	Drain current (continuous) at T_C = 25 °C	110	A
I_D	Drain current (continuous) at T_C = 100 °C	110	A
I_{DM} (1)	Drain current (pulsed)	440	A
P_{TOT}	Total dissipation at T_C = 25 °C	250	W
E_{AS}(2)	Single pulse avalanche energy	495	mJ
T_J	Operating junction temperature	-55 to 175	°C
T_{stg}	Storage temperature		°C

1. Pulse width is limited by safe operating area
2. Starting T_j=25 °C, I_D=30 A, V_{DD}=50 V

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case max	0.6	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient max	62.5	°C/W

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0, I_D = 250 µA	100			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0, V_{DS} = 100 V			1	µA
		V_{GS} = 0, V_{DS} = 100 V, T_C=125 °C			100	µA
I_{GSS}	Gate-body leakage current	V_{DS} = 0, V_{GS} = +20 V			100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	2.5		4.5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 55 A		0.0036	0.0042	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 50 V, f = 1 MHz, V_{GS} = 0	-	8115	-	pF
C_{oss}	Output capacitance		-	1510	-	pF
C_{rss}	Reverse transfer capacitance		-	67	-	pF
Q_g	Total gate charge	V_{DD} = 50 V, I_D = 110 A, V_{GS} = 10 V	-	117	-	nC
Q_{gs}	Gate-source charge		-	47	-	nC
Q_{gd}	Gate-drain charge		-	26	-	nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD} = 50 V, I_D = 55 A, R_G = 4.7 Ω, V_{GS} = 10 V	-	33	-	ns
t_r	Rise time		-	57	-	ns
$t_{d(off)}$	Turn-off delay time		-	72	-	ns
t_f	Fall time		-	33	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		110	A
I_{SDM} (1)	Source-drain current (pulsed)		-		440	A
V_{SD} (2)	Forward on voltage	I_{SD} = 110 A, V_{GS} = 0	-		1.2	V
t_{rr}	Reverse recovery time	I_{SD} = 110 A, di/dt = 100 A/µs V_{DD} = 80 V, T_J=150 °C	-	70		ns
Q_{rr}	Reverse recovery charge		-	165		nC
I_{RRM}	Reverse recovery current		-	4.7		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 µs, duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

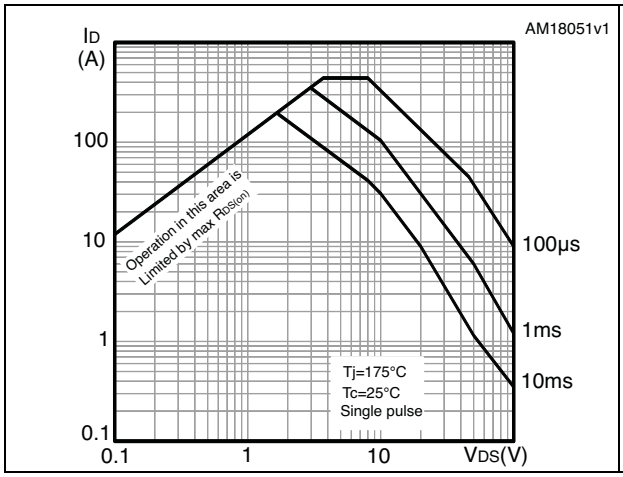


Figure 3. Thermal impedance

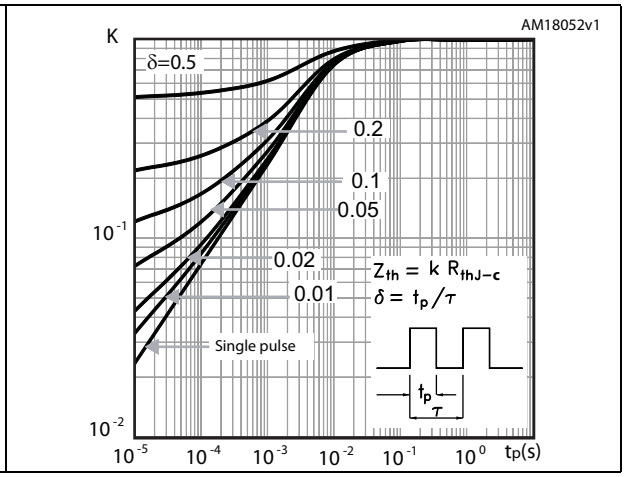


Figure 4. Output characteristics

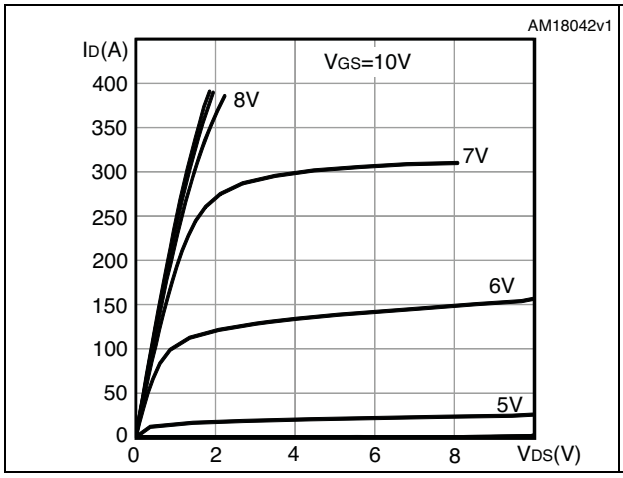


Figure 5. Transfer characteristics

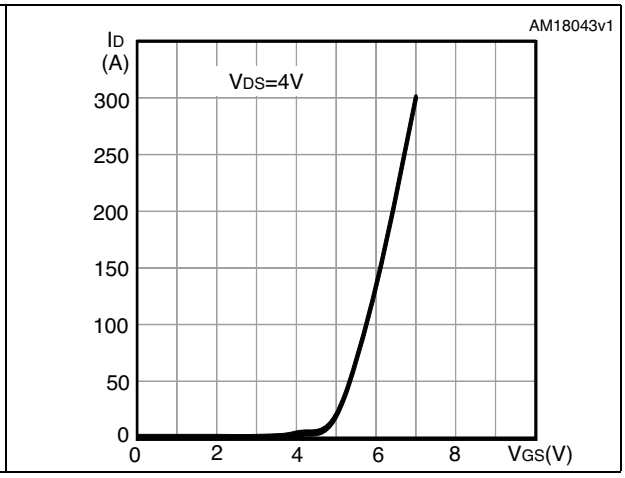


Figure 6. Gate charge vs gate-source voltage

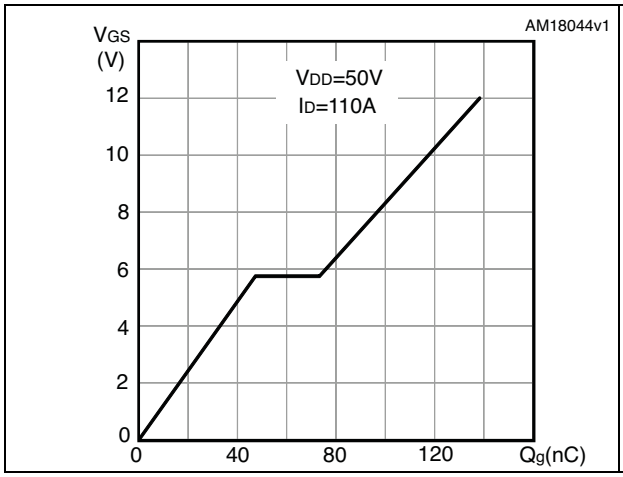


Figure 7. Static drain-source on-resistance